

# **Studying nanomaterials with remarkable properties using advanced x-ray spectroscopies**

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X-ray spectroscopies performed at synchrotron light sources, such as X-ray Absorption Spectroscopy and Resonant Inelastic X-ray Scattering are powerful tools to study complex materials, due to their chemical selectivity that allows disentangling the respective contributions of different atomic species. In this talk, I will show how the use of incident polarized x-rays (either linear or circular) can allow a deeper understanding of the electronic structure and reveal emergent properties, with a focus on remarkable magnetic nanomaterials: Single Molecule Magnets [1], bimagnetic nanoparticles [2], ferrofluids [3], ultra-thin nanowires [4]. Moreover, I will illustrate how the combination of these spectroscopies with x-ray microscopies (scanning transmission x-ray microscopy, ptychography) can provide valuable information with nanoscale spatial resolution, exemplified by recent results obtained on magnetotactic organisms [5].

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